

M5M52B88J-8,-10,-12

262144-BIT (32768-WORD BY 8-BIT) BICMOS STATIC RAM

DESCRIPTION

The M5M52B88 is a family of 32768-word by 8-bit static RAMs, fabricated with the high-performance BiCMOS process and designed for high-speed application. These devices operate on a single 5V supply, and are directly TTL compatible. They include a power-down feature as well.

FEATURES

- Fast access time
 - M5M52B88J-8 8ns(max)
 - M5M52B88J-10 10ns(max)
 - M5M52B88J-12 12ns(max)
- Low power dissipation
 - Active 450mW(typ)
 - Stand by 50mW(typ)
- Power down by \bar{S}
- Center power (Vcc, GND) pin out
- Single 5V power supply
- Fully static operation
- Requires neither external clock nor refreshing
- All inputs and outputs are directly TTL compatible
- Easy memory expansion by chip-select (\bar{S}) input
- Output enable (\bar{OE}) prevents data contention in the I/O bus
- All address inputs are changeable with each other.

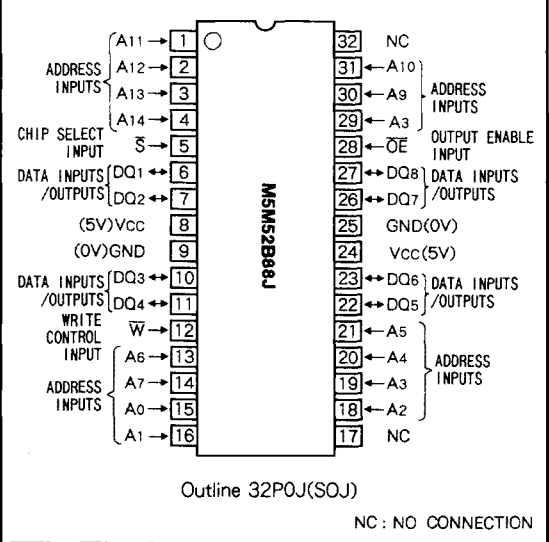
APPLICATION

High-speed memory systems

FUNCTION

A write operation is executed during the \bar{S} low, and \bar{W} low overlap time. In this period, address signals must be stable. When \bar{W} is low, the DQ terminal is maintained in the high impedance state.

PIN CONFIGURATION (TOP VIEW)

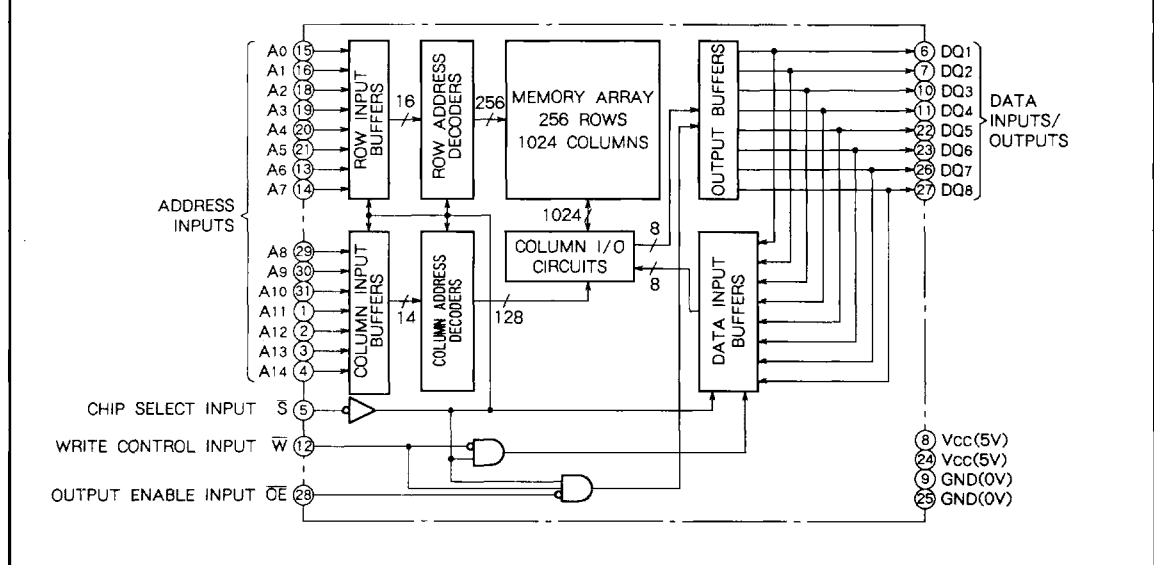


In a read operation, after setting \bar{W} to high, \bar{S} to low, and \bar{OE} to low if the address signals are stable, the data is available at the DQ terminal.

When \bar{S} is high, the chip is in the non-selectable state, disabling both reading and writing. In this case the output is in the floating (high-impedance) state, useful for OR-ties with other devices.

Single \bar{S} controls the power-down feature. When \bar{S} goes high, power dissipation is reduced extremely. The access time from \bar{S} is equivalent to the address access time.

BLOCK DIAGRAM



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MODE SELECTION

\bar{S}	\bar{W}	\bar{OE}	Mode	Data input/output	I_{CC}
H	X	X	Non selection	High-impedance	Stand by
L	L	X	Write	D_{in}	Active
L	H	L	Read	D_{out}	Active
L	H	H		High-impedance	Active

H : V_{IH} L : V_{IL} X : V_{IH} or V_{IL}

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
V_{CC}	Supply voltage	With respect to GND	- 3.5* ~7	V
V_I	Input voltage		- 3.5* ~7	V
V_O	Output voltage		- 3.5* ~7	V
P_d	Maximum power dissipation		1	W
T_{opr}	Operating temperature		0~70	°C
$T_{stg(bias)}$	Storage temperature(bias)		- 10~85	°C
T_{stg}	Storage temperature		- 65~150	°C

* Pulse width \leq 10ns, In case of DC : - 0.5V

DC ELECTRICAL CHARACTERISTICS ($T_a = 0\sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
V_{IH}	High-level input voltage		2.2		$V_{CC}+0.3$	V
V_{IL}	Low-level input voltage		- 0.5*		0.8	V
V_{OH}	High-level output voltage	$I_{OH} = - 4\text{mA}$	2.4			V
V_{OL}	Low-level output voltage	$I_{OL} = 8\text{mA}$			0.4	V
I_I	Input current	$V_I = 0\sim V_{CC}$			2	μA
$ I_{OZ} $	Off-state output current	$V_I(\bar{S}) = V_{IH}, V_O = 0\sim V_{CC}$			10	μA
I_{CC1}	Supply current from V_{CC}	$V_I(\bar{S}) = V_{IL}$ Output open	AC(8ns cycle)		195	mA
			AC(10ns cycle)		185	
			AC(12ns cycle)		175	
			DC	90	115	
I_{CC2}	Stand by current	$V_I(\bar{S}) = V_{IH}$	AC(8ns cycle)		70	mA
			AC(10,12ns cycle)		60	
			Other $V_I \geq V_{IH}$ or $\leq V_{IL}$		50	
I_{CC3}	Stand by current	$V_I(\bar{S}) = V_{CC} - 0.2V$ Other $V_I \leq 0.2V$ or $V_I \geq V_{CC} - 0.2V$			10	mA

Note 1. Current flow into an IC is positive, out is negative.

* - 3.0V in case of AC (Pulse width \leq 10ns)

CAPACITANCE

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C_I	Input capacitance	$V_I = \text{GND}, V_I = 25\text{mVrms}, f = 1\text{MHz}$			5	pF
C_O	Output capacitance	$V_O = \text{GND}, V_O = 25\text{mVrms}, f = 1\text{MHz}$			7	pF

AC ELECTRICAL CHARACTERISTICS ($T_a = 0\sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

(1) MEASUREMENT CONDITIONS

Input pulse levels $V_{IH} = 3V, V_{IL} = 0V$
 Input rise and fall time 3ns
 Input timing reference levels $V_{IH} = 1.5V, V_{IL} = 1.5V$
 Output timing reference levels $V_{OH} = 1.5V, V_{OL} = 1.5V$
 Output loads Fig.1, Fig.2

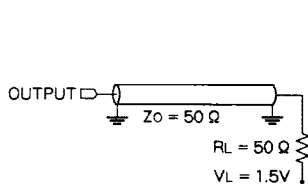


Fig.1 Output load

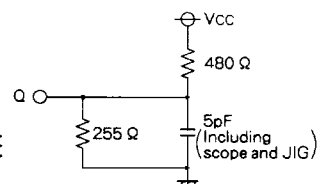


Fig.2 Output load for t_{en}, t_{dis}

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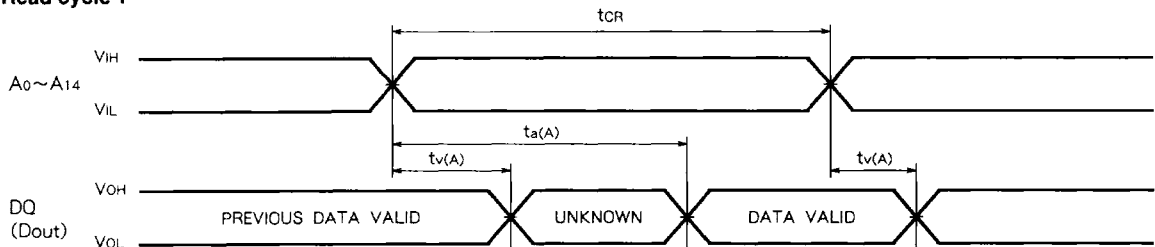
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(2) READ CYCLE

Symbol	Parameter	Limits						Unit
		M5M52B88-8		M5M52B88-10		M5M52B88-12		
		Min	Max	Min	Max	Min	Max	
t _{CR}	Read cycle time	8		10		12		ns
t _{a(A)}	Address access time		8		10		12	ns
t _{a(S)}	Chip select access time		8		10		12	ns
t _{a(OE)}	Output enable access time		4		5		6	ns
t _{v(A)}	Data valid time after address change	3		4		4		ns
t _{en(S)}	Output enable time from(\bar{S})	3		4		4		ns
t _{en(OE)}	Output enable time from(\bar{OE})	3		3		3		ns
t _{dis(S)}	Output disable time from(\bar{S})	0	4	0	5	0	6	ns
t _{dis(OE)}	Output disable time from(\bar{OE})	0	4	0	5	0	6	ns
t _{PU}	Power-up time after chip selection	0		0		0		ns
t _{PD}	Power-down time after chip selection		8		10		12	ns

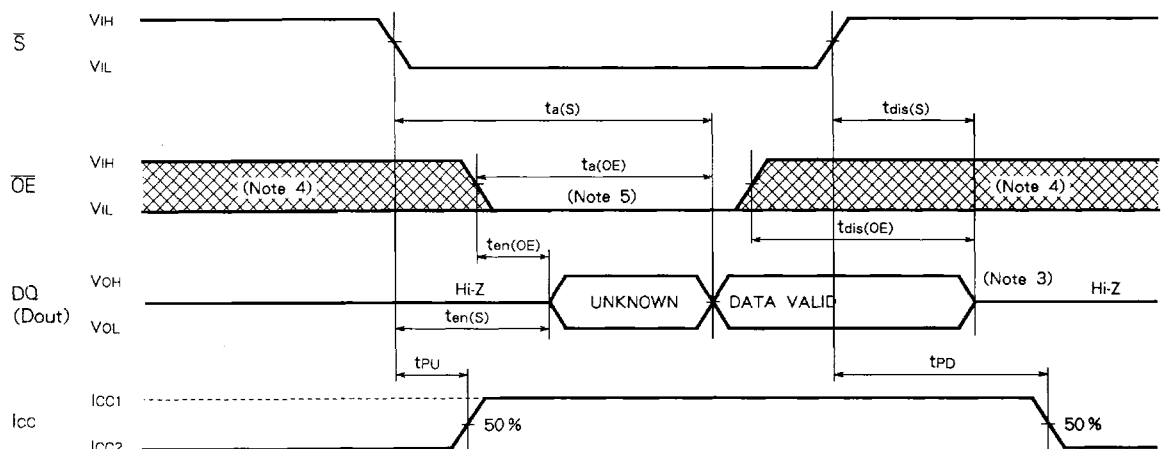
(3) TIMING DIAGRAMS FOR READ CYCLE

Read cycle 1



$\bar{W} = H$ $\bar{S} = L$ $\bar{OE} = L$

Read cycle 2 (Note 2)



$\bar{W} = H$

- Note 2. Addresses valid prior to or coincident with \bar{S} transition low.
- 3. Transition is measured $\pm 500mV$ from steady state voltage with specified loading in Figure2.
- 4. Hatching indicates the state is don't care.
- 5. Addresses and \bar{S} valid prior \bar{OE} transition low by $(t_a(A) - t_a(OE), t_a(S) - t_a(OE))$.

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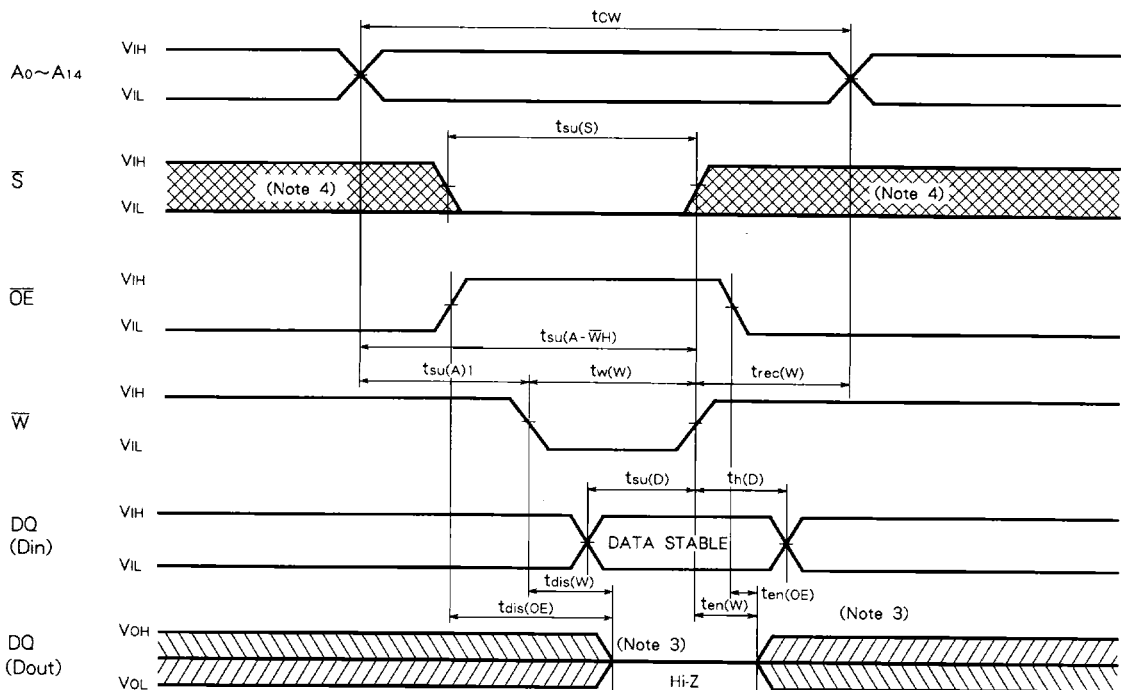
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(4) WRITE CYCLE

Symbol	Parameter	Limits						Unit
		M5M52B88-8		M5M52B88-10		M5M52B88-12		
		Min	Max	Min	Max	Min	Max	
t _{cw}	Write cycle time	8		10		12		ns
t _{su(S)}	Chip select setup time	7		9		10		ns
t _{su(A)1}	Address setup time(\bar{W})	0		0		0		ns
t _{su(A)2}	Address setup time(\bar{S})	0		0		0		ns
t _{w(W)}	Write pulse width	7		9		10		ns
t _{rec(W)}	Write recovery time	0		0		0		ns
t _{su(D)}	Data setup time	4		5		6		ns
t _{h(D)}	Data hold time	0		0		0		ns
t _{dis(W)}	Output disable time from \bar{W}	0	4	0	5	0	6	ns
t _{dis(OE)}	Output disable time from \bar{OE}	0	4	0	5	0	6	ns
t _{en(W)}	Output enable time from \bar{W}	0		0		0		ns
t _{en(OE)}	Output enable time from \bar{OE}	0		0		0		ns
t _{su(A-\bar{W}H)}	Address to \bar{W} high	7		9		10		ns
t _{su(A-\bar{S}H)}	Address to \bar{S} high	7		9		10		ns

(5) TIMING DIAGRAMS FOR WRITE CYCLE

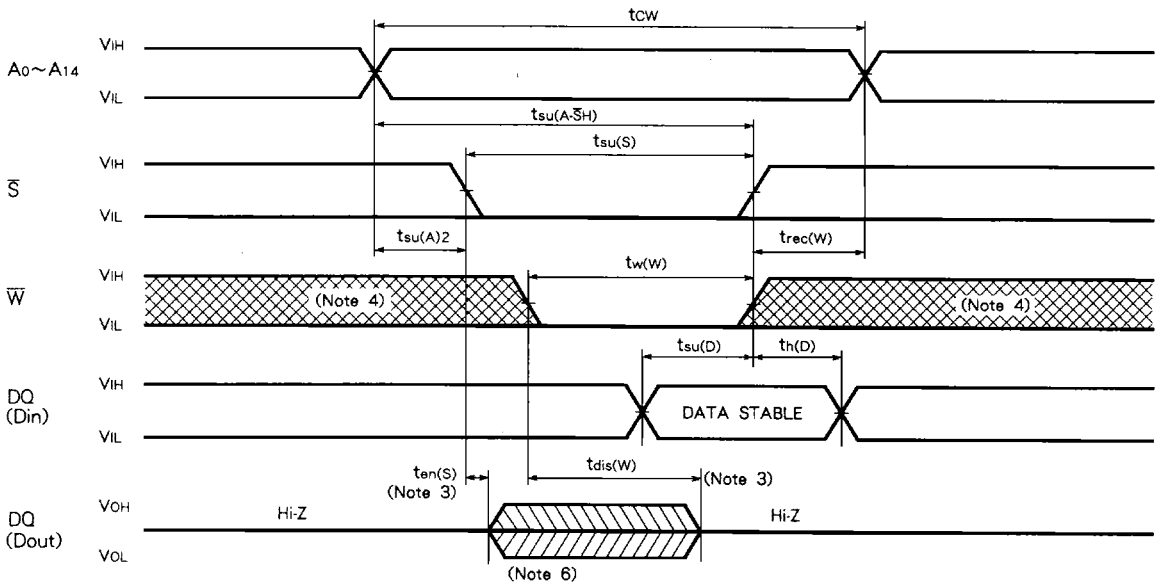
Write cycle 1 (\bar{W} control mode)



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Write cycle 2 (\bar{S} control mode)



Note 6. When the falling edge of \bar{W} is simultaneous or prior to the falling edge of \bar{S} , the output is maintained in the high impedance.